

<b>Notice of References Cited</b>	Application/Control No. 09/937,520	Applicant(s)/Patent Under Reexamination MITANI ET AL.	
	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1

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MITANI ET AL.Examiner  
Rip A. LeeArt Unit  
1713

Page 1 of 1

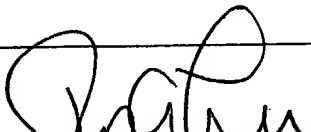
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	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1

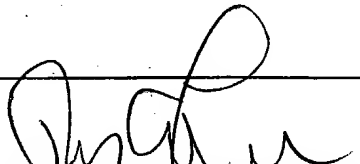
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